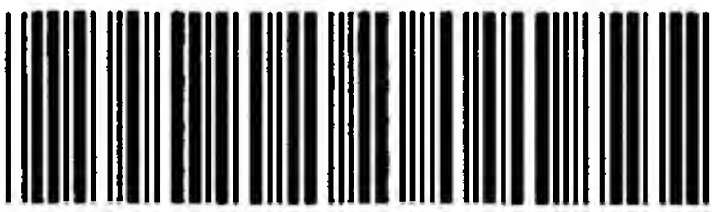


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/533,267	HAGIWARA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Anthony Weier	1761	

SEARCHED			
Class	Subclass	Date	Examiner
updated	previous search	2/14/2007	AW

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR